

Angular and Position resolution

Michele Faucci Giannelli

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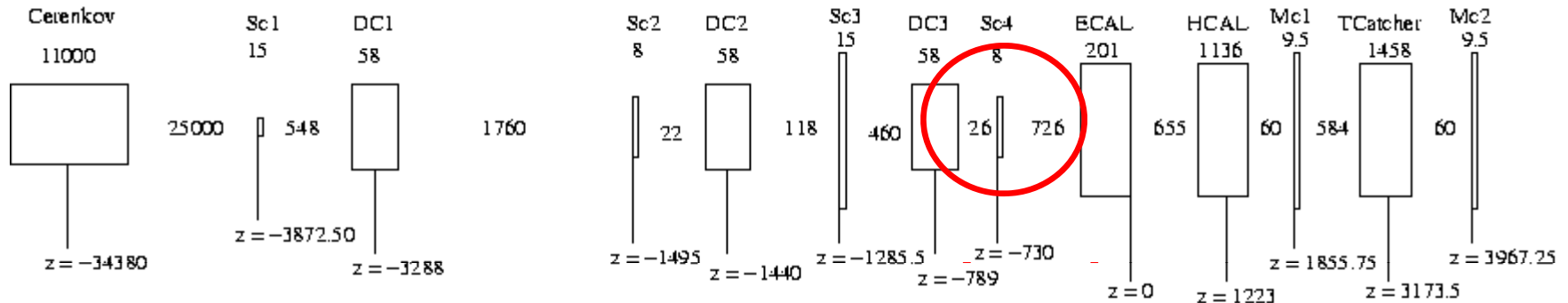
- Introduction:
 - Beam line in 2006
- Event selection
- Angular resolution
- Position resolution
 - S-curve correction
- First look at systematic errors:
 - Tracking
 - Selection effect
- Conclusion



Beam Line in 2006

H6 Area at CERN

TOP

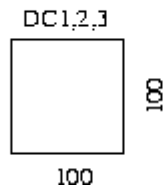


FRONT

Sc1 is 30x30

Sc2 and Sc4 are 100x100

Sc3 is 200x200



Mc1 and Mc2 are 1000x1000

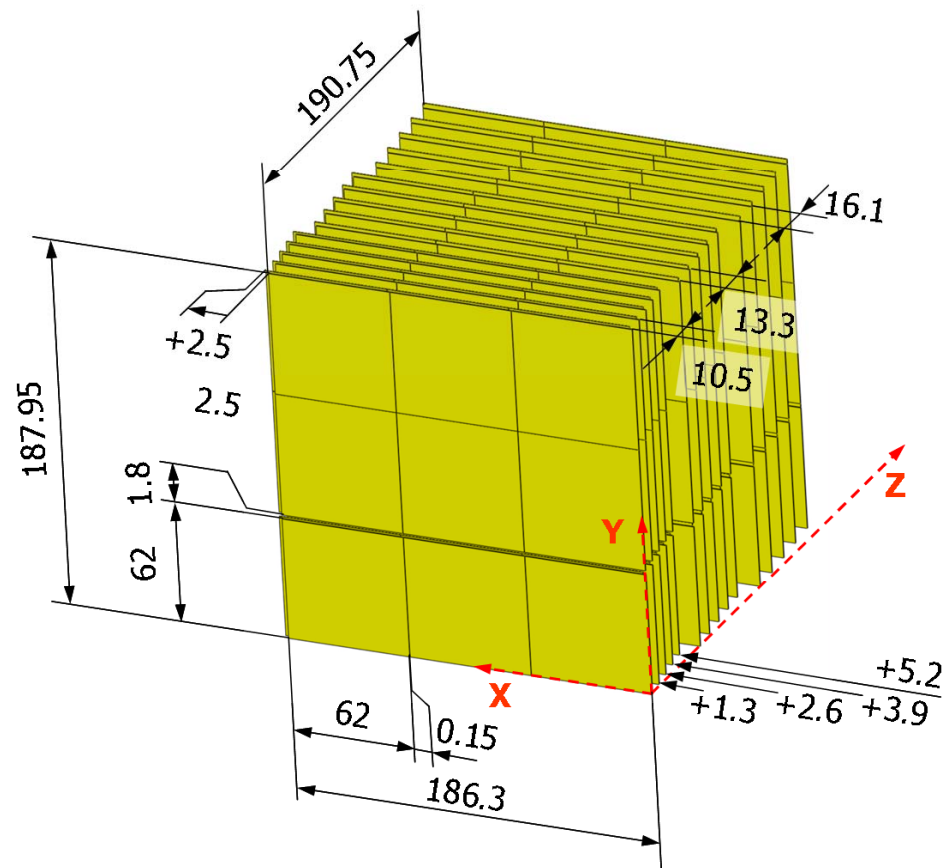
All distances are in mm

In principle this is the best period to study position resolution as the DC3-Ecal distance was the smallest among all test beam periods

No survey for tracking alignment

No Calibration for the drift chambers (2007 values should be usable)

- Only top 3×2 wafers installed
- Staggering on X
 - 2.5 mm between the two layers in a slab
 - 1.3 mm between slabs in each sector
- No staggering on Y





- The same runs used for the energy resolution paper were used for this study

Run	Energy (GeV)
300670	6
300672	10
300235	15
300236	20
300207	30
300202	40
300208	45

- Reconstruction version is the latest available: reco_v0406
- Electrons were selected in each run using the paper selection:
 - 0.6 MIP threshold
 - $0.5 E_{\text{peak}} < E < 1.5 E_{\text{peak}}$
 - Cherenkov
 - Single cluster: T_{max}



- Official tracking is available for these runs
 - Some parameters still need to be fine-tuned
- Required both direction to be well reconstructed
 - Chi - Probability > 0.1
- If more than one track is reconstructed, the best one (highest probability) is chosen
- Both directions are required or the event is discarded

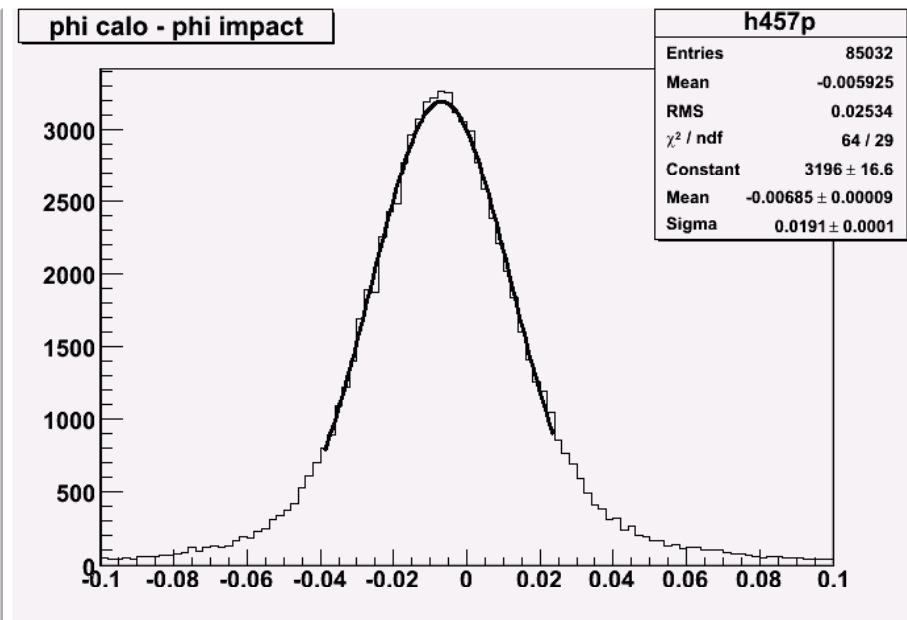
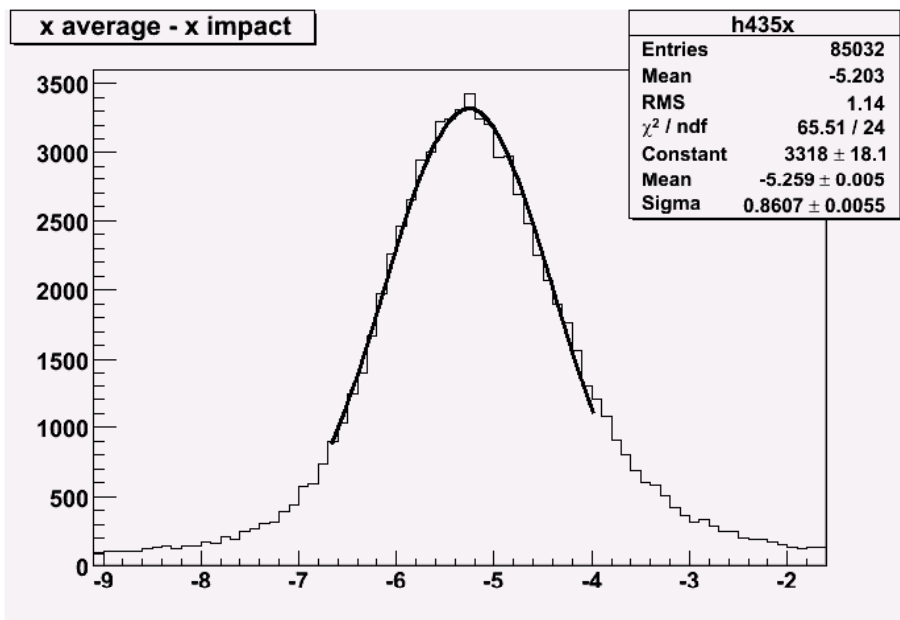


The position resolution is evaluated from the distribution of

$$X_{\text{ECAL}} - X_{\text{Track}}$$

The same is done for the angles along the planes X-Z and Y-Z

$$\text{Angle}_{\text{ECAL}} - \text{Angle}_{\text{Track}}$$

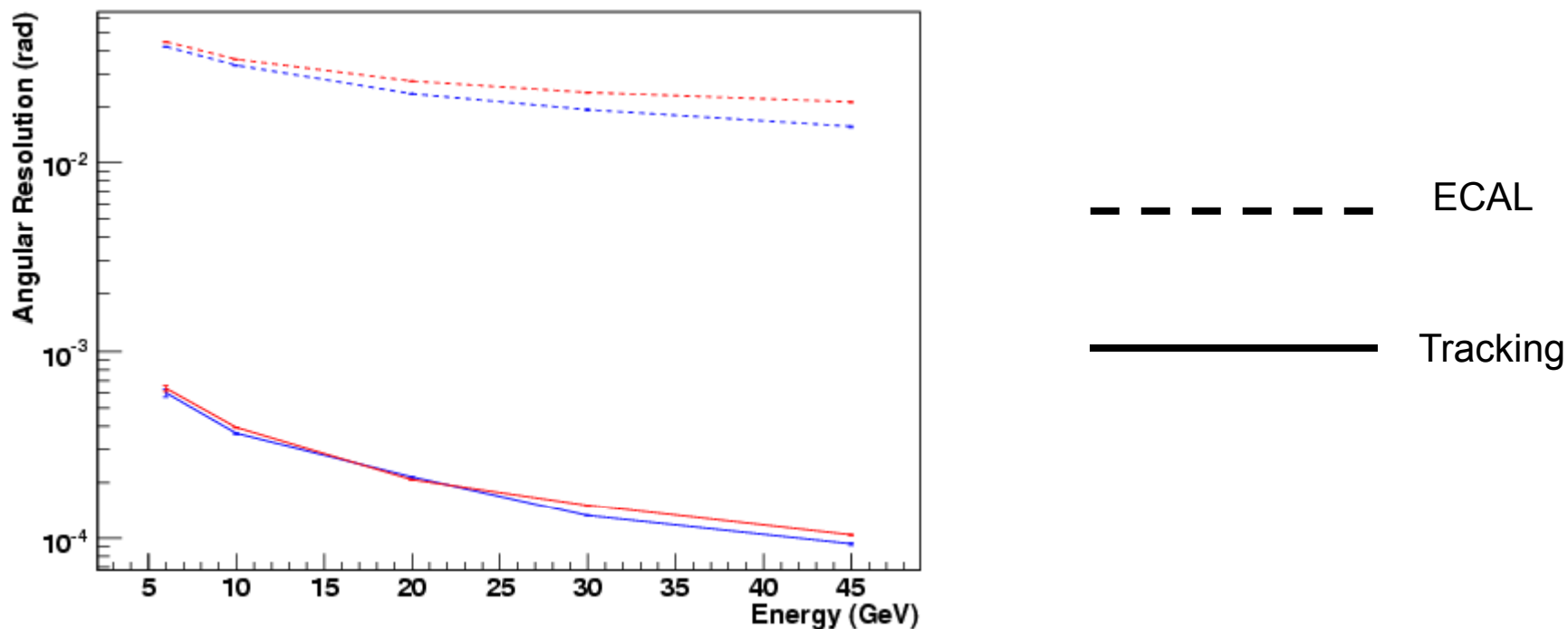


A first fit is performed without imposing a range, then the fit is iterated in the range $(-\sigma, +\sigma)$ until the difference between the fitted mean and the previous one is smaller than the error on the mean.

The sigma of the latest fit is the resolution.



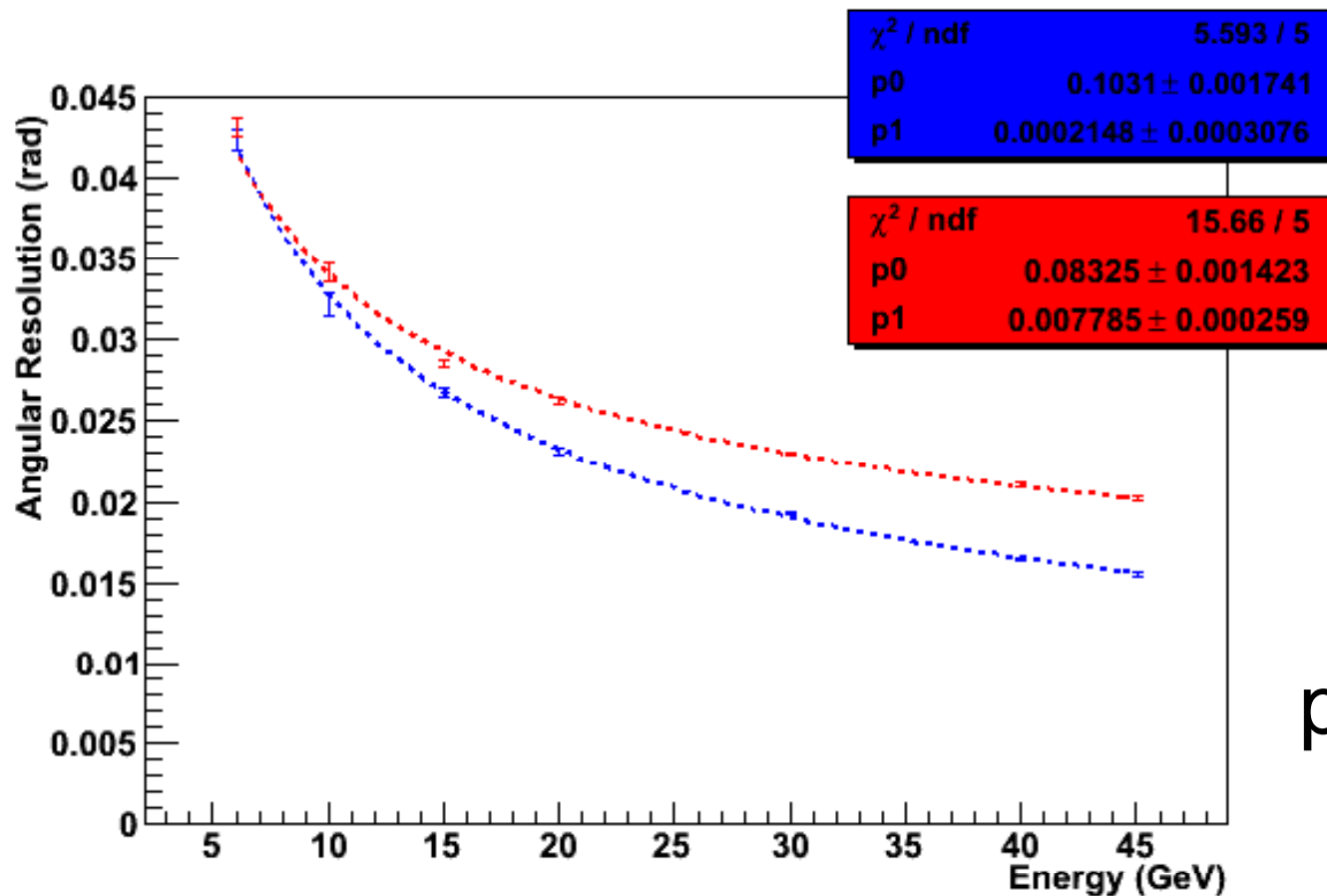
In MC, TRUE entry point and entry angle are compared to reconstructed value from ECAL and Tracking



Tracking should not affect the angular resolution



Angular resolution



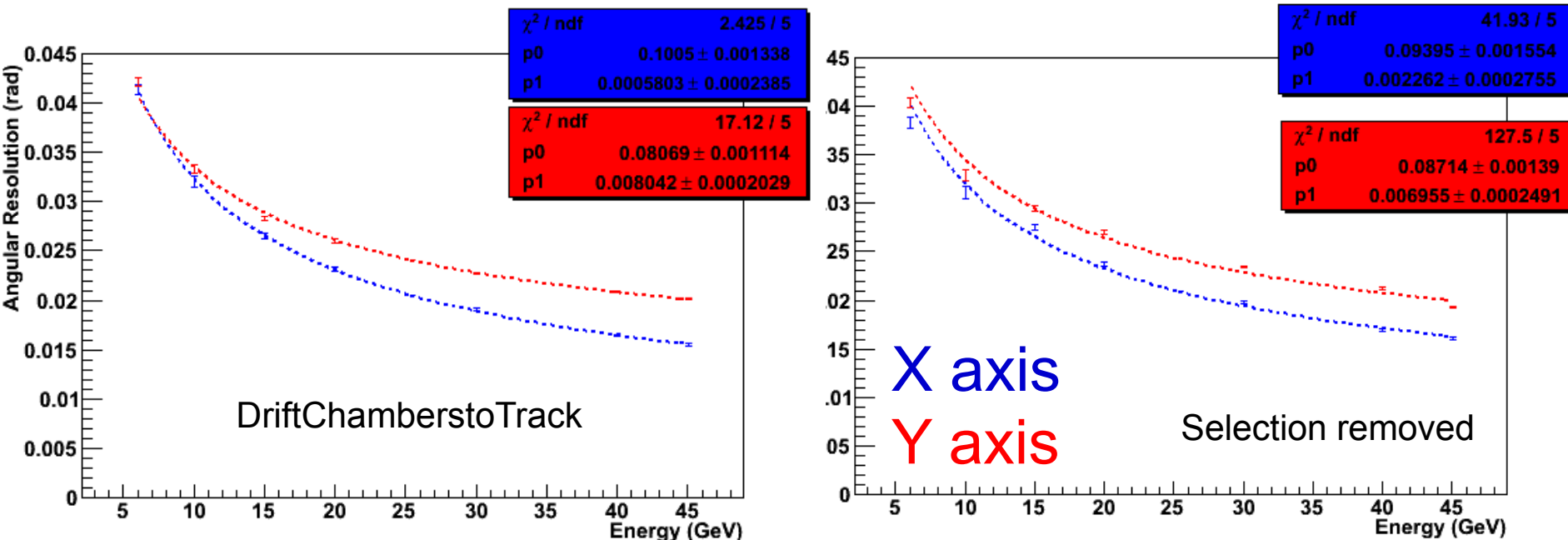
X axis

Y axis

- The difference between axis is explained by the different width of the ECAL:
 - 2 wafers along Y, 3 along X



Angular resolution



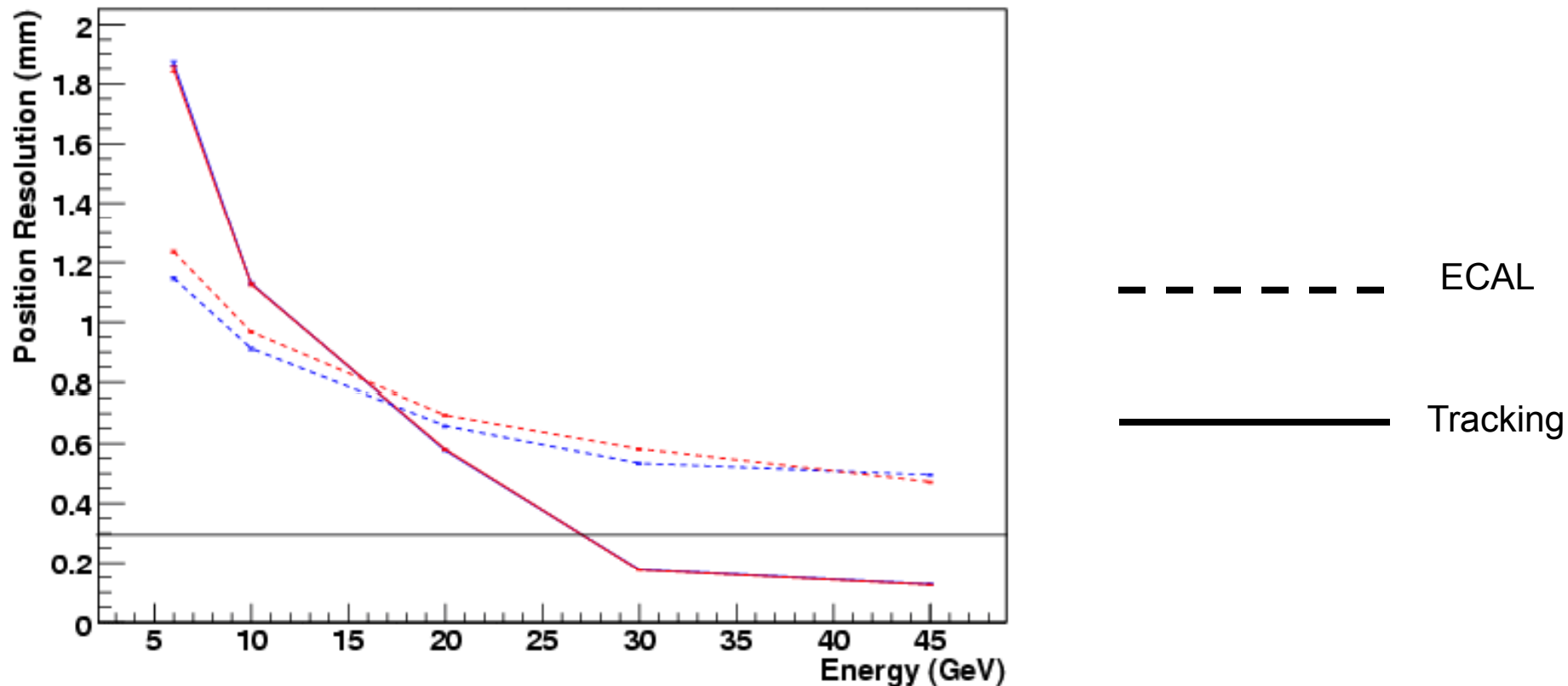
Comparison along X axis

Tracking	Official	Simple	No selection
p0 (mrad)	103.1 ± 1.7	100.5 ± 1.3	94 ± 2
p1 (mrad)	0.2 ± 0.3	0.6 ± 0.2	2.2 ± 0.3

Selection has larger effect than tracking (as expected)



From MC is possible to evaluate the different contributions to the position resolutions



The continuous line is the contribution from intrinsic resolution of tracking chambers

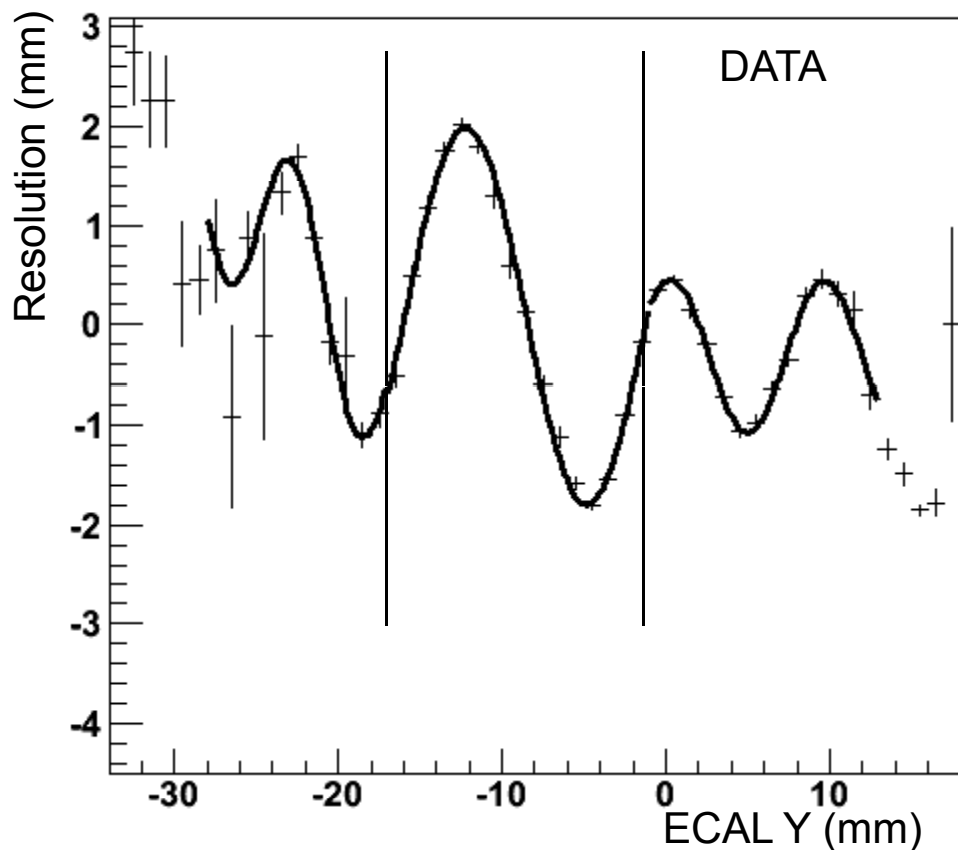


- Cell structure of ECAL causes an increase of the ECAL resolution
- The resolution ($X_{\text{ECAL}} - X_{\text{Track}}$) is zero if the particle hits the centre of a cell but is different from zero (thus increasing the sigma of the distribution) if the hit happens anywhere else
- Plotted as a function of the ECAL position, the resolution has a sinusoidal behavior
- The presence of gaps between wafers has to be taken into account



S-curve (Y)

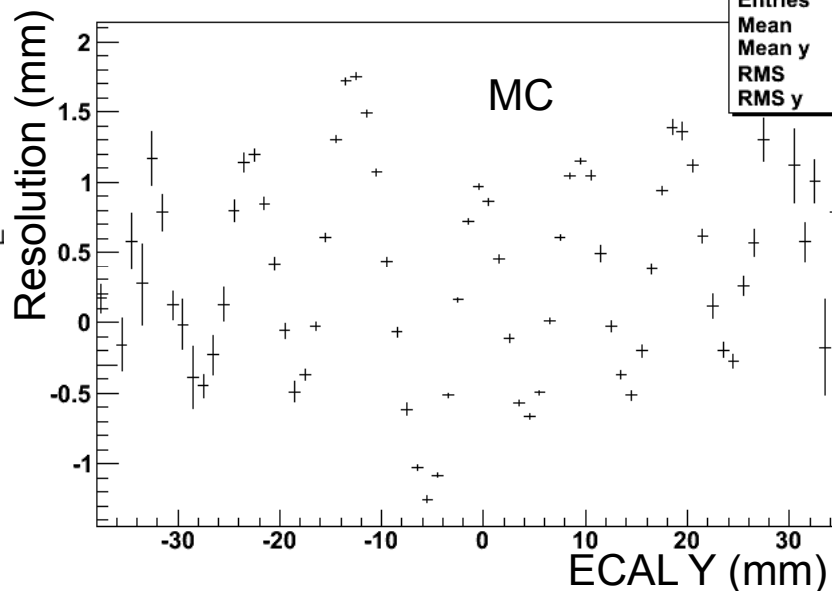
y average - y impact vs y average



h435_cory	
Entries	78461
Mean	-0.3283
Mean y	-0.3017
RMS	8.307
RMS y	3.795

Three region of fit to take in account the gap

y average - y impact vs y average



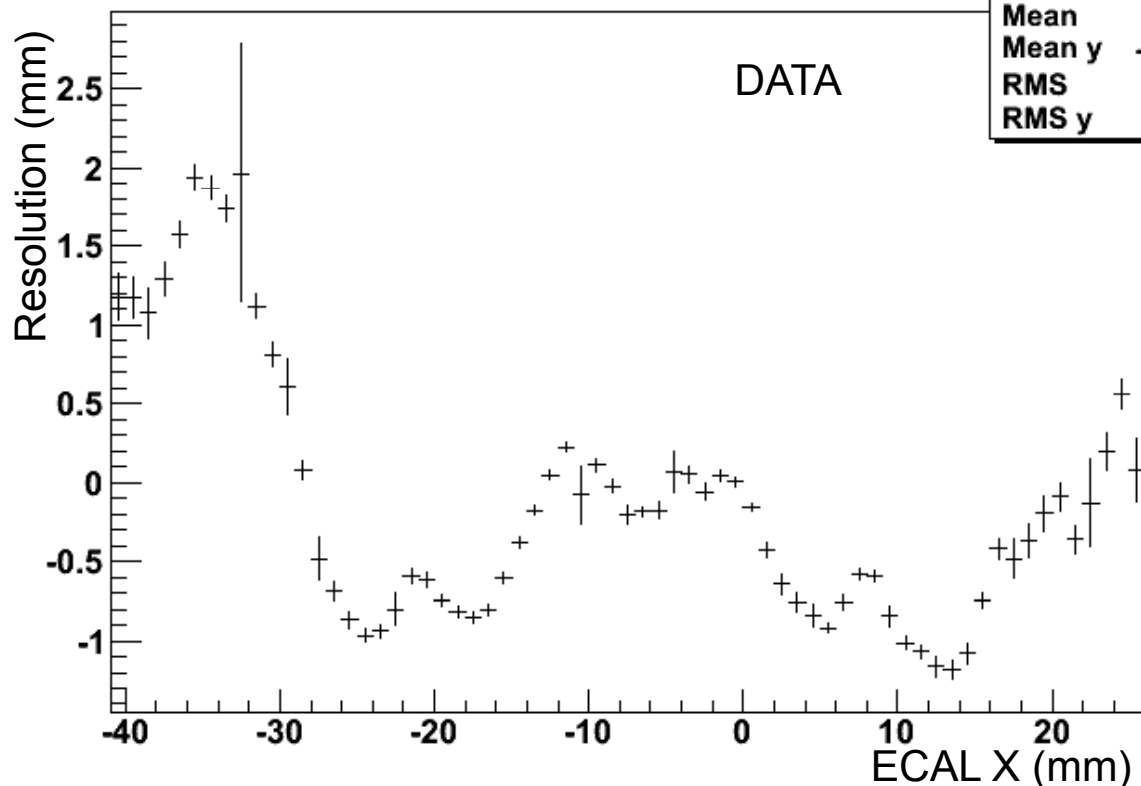
h435_cory	
Entries	93295
Mean	-0.184
Mean y	0.1826
RMS	9.127
RMS y	1.417

Good agreement with MC



S-curve (X)

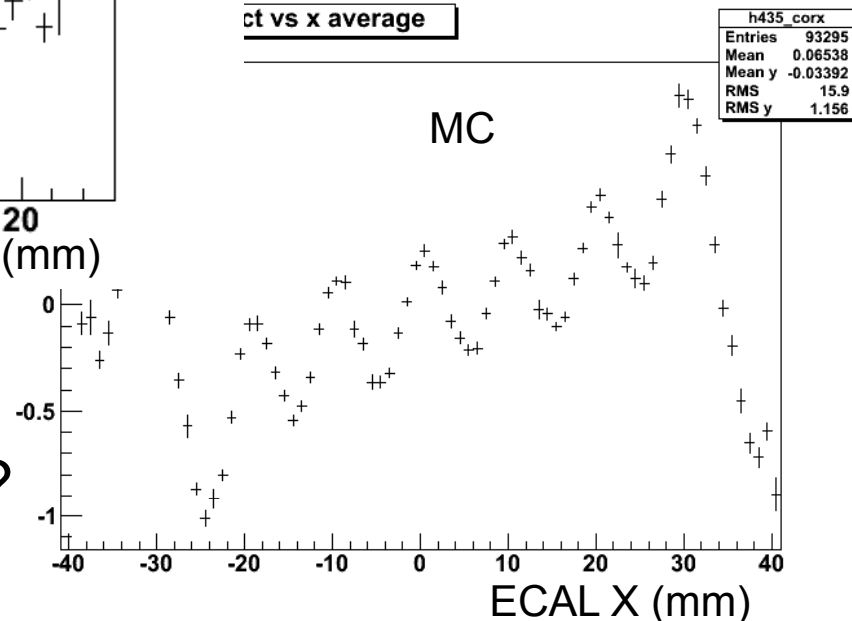
x average - x impact vs x average



h435_corx	
Entries	78461
Mean	-3.79
Mean y	-0.3705
RMS	13.45
RMS y	2.678

Difficult to correct for cell structure

ct vs x average

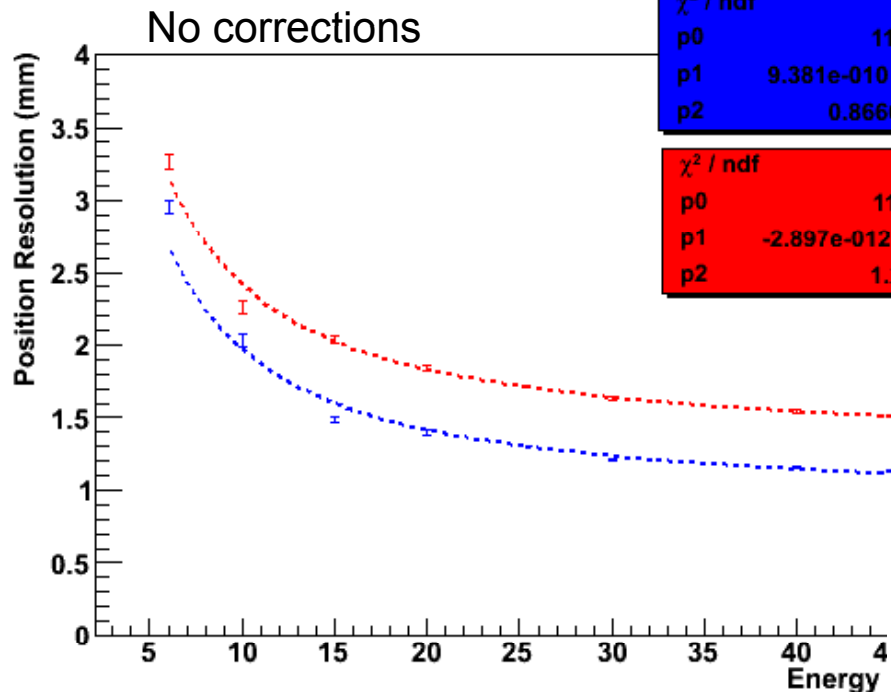


h435_corx	
Entries	93295
Mean	0.06538
Mean y	-0.03392
RMS	15.9
RMS y	1.156

Does the MC include all staggering?



Effect of correction

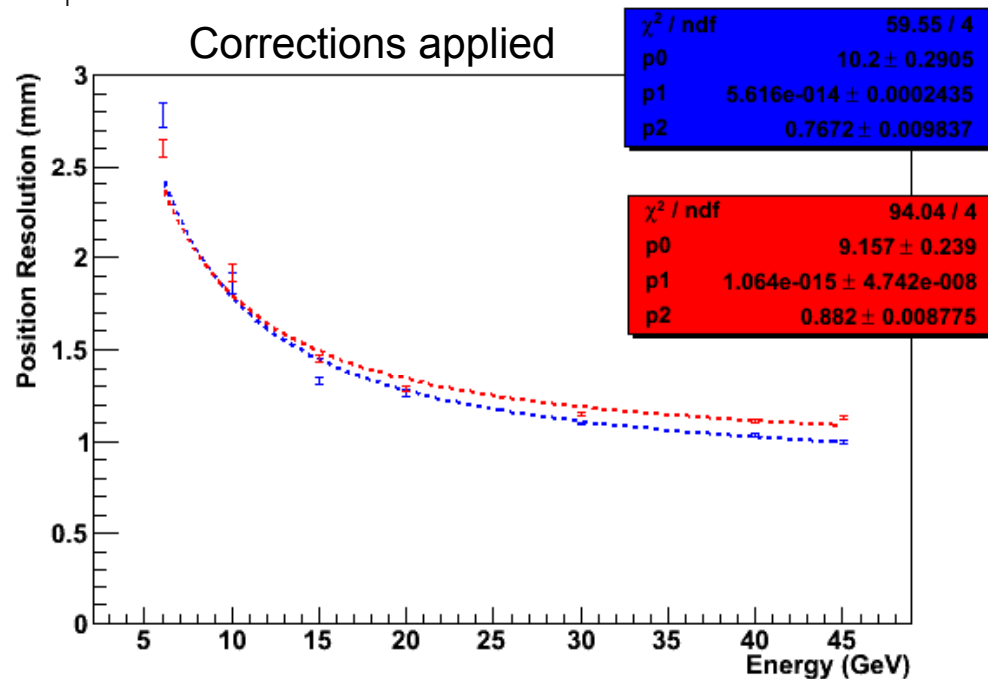


X axis

Y axis

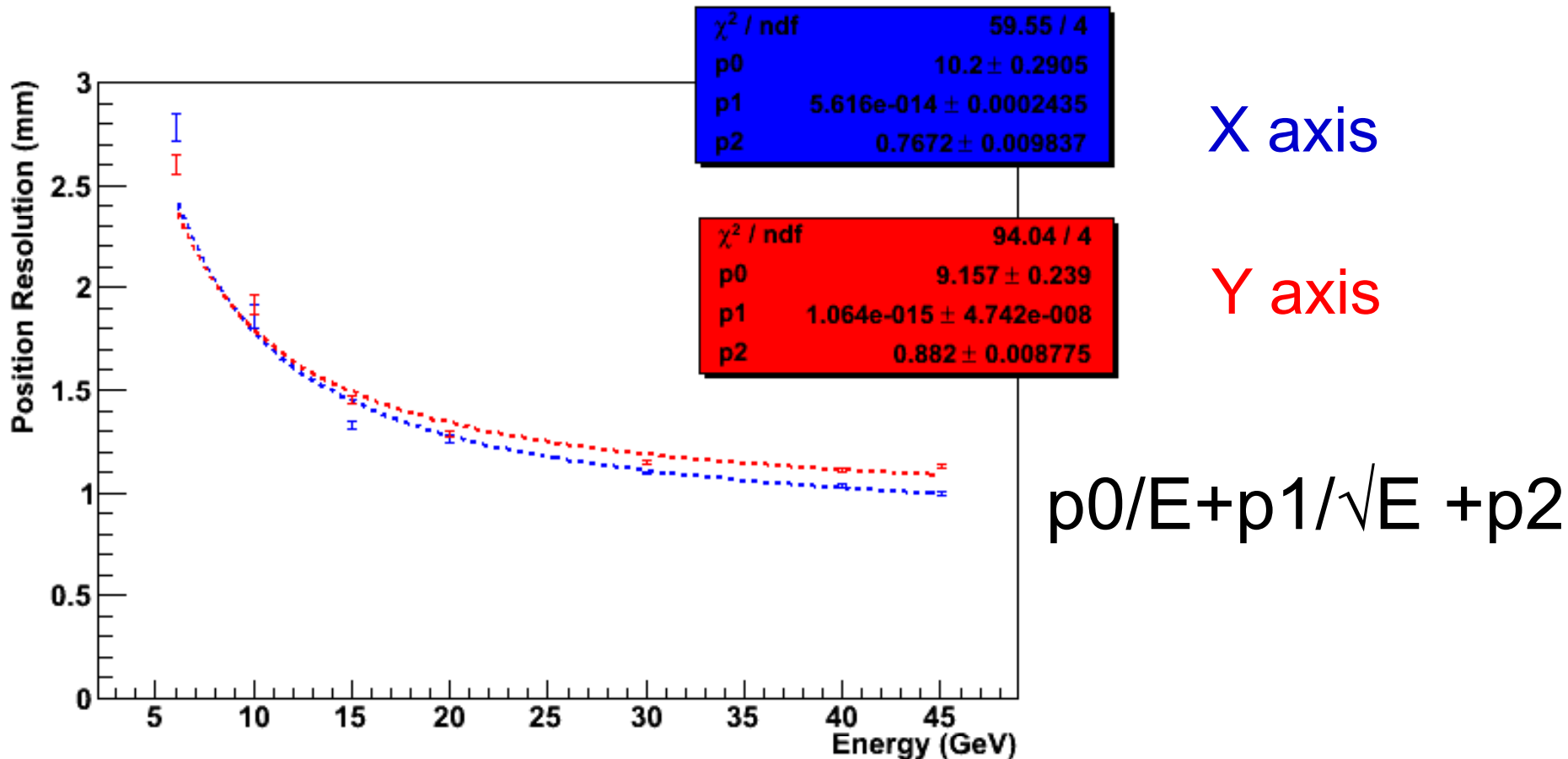
Large improvement
especially along Y

(at 45 GeV from 1.6 mm to 1.2 mm)





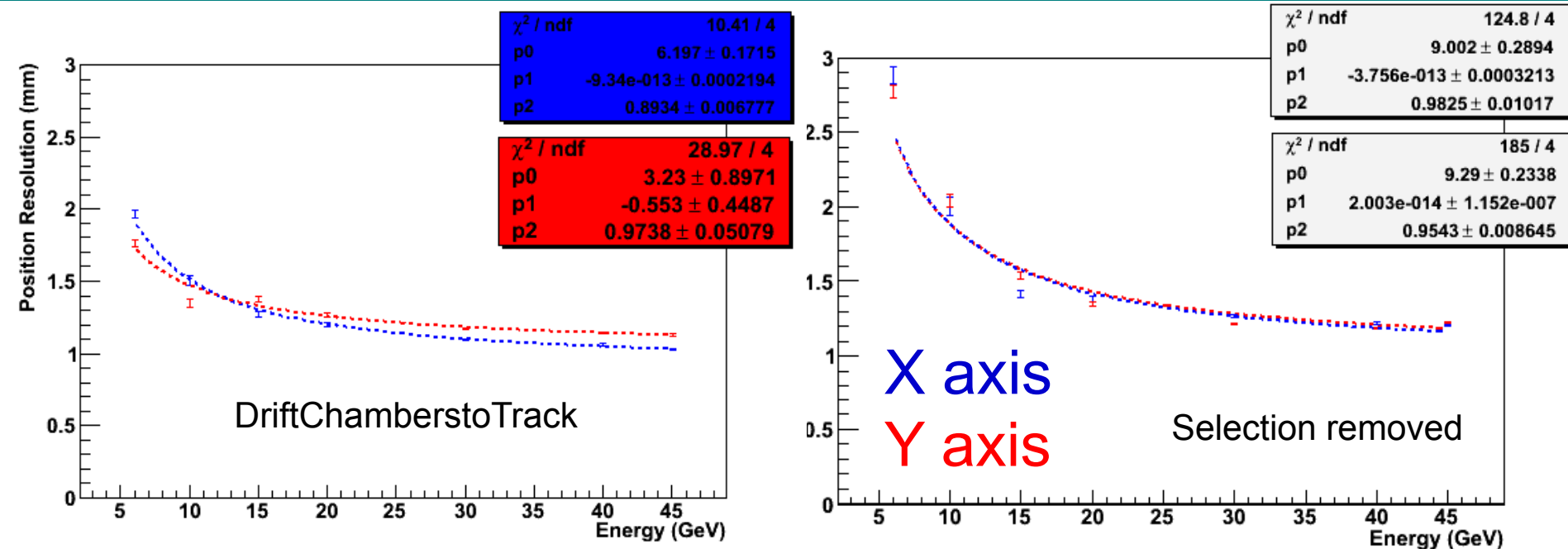
Position resolution



Fit has poor quality and term scaling as $1/\sqrt{E}$ is 0
Likely due to a high contribution from tracking



Position resolution



For the points not affected by MS (above 20 GeV) the results from simple tracking and official tracking are similar, the fit is different because of the low energy points

The selection of the electrons has a larger impact on the results
Need to perform a deeper study to find what is the main cause and how our cut are affected



- Position and angular resolution are under study:
 - several problems to be understood
 - the core of analysis is ready and it is possible to study several effects
- Focus on systematic errors:
 - Large effect from selection: pions or pre-shower? how much dependent on cut values?
 - Hit threshold
 - Limits of fits (S-curve, final fit, Gauss fit)
- Need the updated MC files
 - with reconstructed tracks and entry point in ECAL